Test Procedure for the NCP1421

ON Semiconductor

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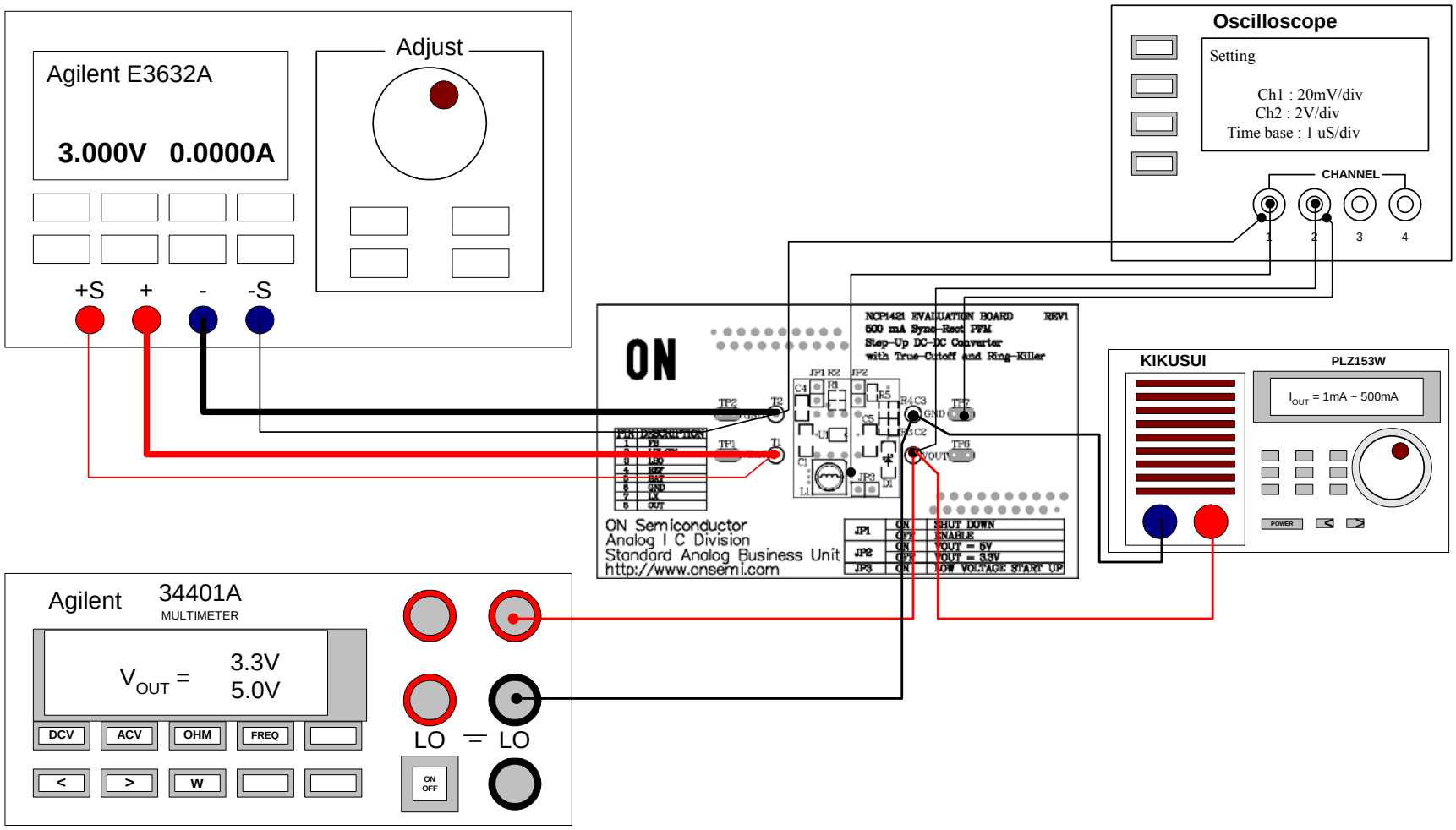

Test Procedure:

1. Connect the test setup as shown above.
2. **Turn OFF the JP1**; (Enable the device).
3. Set the Power Supply to 3.0V and apply to TP1, TP2 (T1, T2).
4. Apply 500mA loading from the electronic load.
5. Check the input current (I_{IN}), output voltage (V_{OUT}) and output ripple;
   - For V_{OUT} = 3.3V; **JP2 OFF**
     I_{IN} = 590.7mA ~ 608.7mA
     V_{OUT} = 3.267 ~ 3.367V
     $V_{RIPPLE} \leq$ 35mV
   - For V_{OUT} = 5V; **JP2** ON
     I_{IN} = 931.07mA ~ 957.4mA
     V_{OUT} = 4.859 ~ 5.0075V
     $V_{RIPPLE} \leq$ 40mV
6. Check the switching waveform at scope CH1 to see whether it is a normal continuous conduction mode switching node waveform and switching ON time (T_{ON}) is between 0.46μs ~ 1.15μs.